

Test report No.

: 28AE0160-HO-A-R1 : 1 of 49

Page

Issued date

: October 1, 2007

Revised date FCC ID : November 8, 2007 : OZGV680-CHXD

# **RADIO TEST REPORT**

Test Report No.: 28AE0160-HO-A-R1

**Applicant** 

: OMRON Corporation

**Type of Equipment** 

RFID READER/WRITER

Model No.

V680-CH1D,

V680-CHUD, V680-CH1D-PSI

Test standard

FCC Part 15 Subpart C: 2007

Section 15.207 and 15.225

FCC ID

:

OZGV680-CHXD

**Test Result** 

Complied

- This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with above regulation.
- 4. The test results in this report are traceable to the national or international standards.
- 5. Original test report number of this report is 28AE0160-HO-A.

Date of test:

September 11 to 18, 2007

Tested by:

Kenichi Adachi EMC Services

Approved by:

Tym

Mitsuru Fujimura EMC Services



200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.

\*As for the range of Accreditation in NVLAP, you may

This laboratory is accredited by the NVLAP LAB CODE

refer to the WEB address, http://uljapan.co.jp/emc/nvlap.htm

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone

: +81 596 24 8116

Facsimile

: +81 596 24 8124

Test report No. : 28AE0160-HO-A-R1
Page : 2 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

CONTENTS	PAGE
SECTION 1: Client information	3
SECTION 2: Equipment under test (E.U.T.)	3
SECTION 3: Test specification, procedures & results	4
SECTION 4: Operation of E.U.T. during testing	
SECTION 5: Conducted emission	
SECTION 6: Radiated emission (Fundamental, Spurious Emission and Spec	
SECTION 7: 20dB Bandwidth	
SECTION 8: Frequency Tolerance	11
SECTION 9: 99% Occupied Bandwidth	
APPENDIX 1: Photographs of test setup	
Conducted emission	
Radiated emission	
Worst Case Position (Y-axis)	
APPENDIX 2: Data of EMI test	
Conducted emission	19
Radiated emission(Fundamental emission and Spectrum Mask)	34
Radiated emission (Spurious emission: above 30MHz)	43
20dB Bandwidth	
99% Occupied Bandwidth	
Frequency Tolerance	
APPENDIX 3: Test instruments	

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 28AE0160-HO-A-R1
Page : 3 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### **SECTION 1: Client information**

Company Name : OMRON Corporation

Address : 2-2-1 Nishi-kusatsu, Kusatsu-city, Shiga-Pref., 525-0035 Japan

Telephone Number : +81-77-565-5287 Facsimile Number : +81-77-565-5553 Contact Person : Kazushi Yamasaki

### **SECTION 2:** Equipment under test (E.U.T.)

#### 2.1 Identification of E.U.T.

Type of Equipment : RFID READER/WRITER

Model No. : V680-CH1D,

V680-CHUD, V680-CH1D-PSI

Serial No. : RF-DS-07011 (V680-CH1D),

RF-DS-07014 (V680-CHUD), RF-DS-07012 (V680-CH1D-PSI)

Rating : DC 5.0V Country of Manufacture : Japan

Receipt Date of Sample : September 10, 2007 Condition of EUT : Production model

Modification of EUT : No modification by the test lab.

### 2.2 Product Description

Model No: V680-CH1D, V680-CHUD and V680-CH1D-PSI are the RFID READER/WRITER. The clock frequencies of EUT are 13.56MHz (CPU), 16MHz(CPU), 48MHz(USB, V680-CHUD only).

The radio specification of V680-CH1D, V680-CHUD and V680-CH1D-PSI is identical.

The difference in three models is a wired interface only.

V680-CH1D
 The RS-232C interface and the power was supplied from the attached AC adapter.
 V680-CHUD
 The USB interface and the power was supplied from the USB signal cable.

USB signal cables are 1.9m and 0.8m, and a difference in two cables is the length only.

- V680-CH1D-PSI : The RS-232C interface and the power was supplied from the RS-232C signal cable.

Equipment Type : Transceiver

Frequency band : 13.553-13.567 MHz

Frequency of Operation : 13.56 MHz
Type of modulation : ASK
Antenna Type : Coil antenna
Method of Frequency Generation : Crystal
Operating voltage (inner) : DC5.0V

Operating Temperature : 0 deg. C. to +40 deg. C.

# UL Japan, Inc.

**Head Office EMC Lab.** 

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 28AE0160-HO-A-R1
Page : 4 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### **SECTION 3:** Test specification, procedures & results

## 3.1 Test Specification

Test Specification : FCC Part15 Subpart C : 2007

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional

Radiators

Section 15.207 Conducted limits

Section 15.225: Operation within the band 13.110-14.010MHz

### FCC 15.31 (e)

This EUT provides stable voltage(DC4.3V) constantly to RF Module regardless of input voltage. Therefore, this EUT complies with the requirement.

### FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 28AE0160-HO-A-R1
Page : 5 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### 3.2 Procedures and results

No.	Item	<b>Test Procedure</b>	Specification	Remarks	Deviation	Worst margin	Results	
1	Conducted emission	ANSI C63.4:2003 7. AC powerline conducted emission measurements <ic>RSS-Gen 7.2.2</ic>	Section 15.207 <ic>RSS-Gen 7.2.2</ic>	-	N/A	(V680-CH1D) 1.6dB 0.24836MHz N, AV	Complied	
2	Electric Field Strength of Fundamental Emission	ANSI C63.4:2003 13. Measurement of intentional radiators <ic> RSS-Gen 4.8, 4.11</ic>	Section 15.225(a) <ic>RSS-210 A2.6</ic>	Radiated	N/A	(V680-CH1D-PSI) 60.0dB 13.56019MHz 90deg., QP	Complied	
3	Spectrum Mask	ANSI C63.4:2003 13. Measurement of intentional radiators <ic>RSS-Gen 4.9, 4.11</ic>	Section 15.225(b)(c) <ic> RSS-210 A2.6</ic>	Radiated	N/A	See data	Complied	
4	20dB Bandwidth	ANSI C63.4:2003 13. Measurement of intentional radiators <ic> -</ic>	Section15.215(c) <ic> -</ic>	Radiated	N/A	See data	Complied	
5	Electric Field Strength of Spurious Emission	ANSI C63.4:2003 13. Measurement of intentional radiators <ic>RSS-Gen 4.9, 4.11</ic>	Section15.209, Section 15.225 (d) <ic>RSS-210 A2.6</ic>	Radiated	N/A	(V680-CH1D) 15.4dB 81.369MHz Vertical, QP	Complied	
6	Frequency Tolerance	ANSI C63.4:2003 13. Measurement of intentional radiators <ic>RSS-Gen 4.7</ic>	Section15.225(e) <ic> RSS-210 A2.6</ic>	Radiated	N/A	See data	Complied	
Note	Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15							

<sup>\*</sup>These tests were performed without any deviations from test procedure except for additions or exclusions.

### 3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Radiated	N/A	N/A	Complied
	Band Width						

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 28AE0160-HO-A-R1
Page : 6 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### 3.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

#### **Conducted Emission**

The measurement uncertainty for this test is  $\pm 2.6$ dB.

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

#### **Spurious Emission (Radiated)**

9kHz to 30MHz: The measurement uncertainty for this test using Loop antenna is  $\pm 4.41dB(3m)/\pm 4.39dB(10m)$ . 30MHz to 300MHz: The measurement uncertainty for this test using Biconical antenna is  $\pm 4.59dB(3m)/\pm 4.58dB(10m)$ . The measurement uncertainty for this test using Logperiodic antenna is  $\pm 4.62dB(3m)/\pm 4.60dB(10m)$ .

Above 1GHz: The measurement uncertainty for this test using Horn antenna is  $\pm 5.27$ dB.

The data listed in this test report has enough margin, more than the site margin.

### 3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. \*NVLAP Lab. code: 200572-0

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN Telephone : +81 596 24 8116 Facsimil

Telephone : +8	81 596 24 8116	Facsimile			_
	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other
No.1 semi-anechoic chamber	313583	IC4247	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	IC4247-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	IC4247-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	IC4247-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-

<sup>\*</sup> Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

### 3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

### UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 28AE0160-HO-A-R1
Page : 7 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### **SECTION 4: Operation of E.U.T. during testing**

#### 4.1 Operating Modes

Test	Mode	Tag
Radiated emission		Without Tag
Bandwidth and	Transmitting (13.56MHz, Modulation, PN9)	With Tag
Conducted emission		
Frequency Tolerance	Transmitting (13.56MHz, None Modulation)	Without Tag

<sup>\*</sup> The test was confirmed with and without a tag in the preliminary test. As a result of preliminary test, since the worst levels for each test were as mentioned above, the formal test was performed under the above conditions.

Justification: The system was configured in typical fashion (as a customer would normally use it) for testing.

Frequency Tolerance:

Temperature for the extreme tests : -30 deg.C.(minimum) to +50deg.C.(maximum)

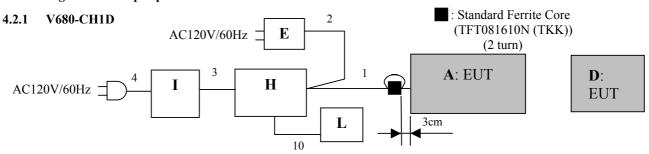
(-30deg.C.: Reference, Step 10deg.C.)

Voltage for the extreme tests : DC 5.0V

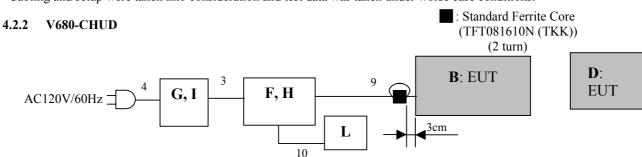
\*This EUT provides stable voltage(DC5.0V) constantly to

RF Module regardless of input voltage.

### 4.2 Configuration and peripherals



\* Cabling and setup were taken into consideration and test data was taken under worse case conditions.



<sup>\*</sup> Cabling and setup were taken into consideration and test data was taken under worse case conditions.

# UL Japan, Inc.

### **Head Office EMC Lab.**

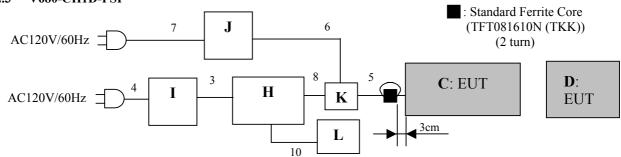
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

<sup>\*</sup> Although the radio specification of three models is identical, Conducted emission and Radiated emission tests were performed with three models. Bandwidth and Frequency Tolerance tests which were less affected by the chassis were performed with a representative model, V680-CH1D-PSI which had the worst carrier level.

Test report No. : 28AE0160-HO-A-R1 Page : 8 of 49 **Issued date** : October 1, 2007 Revised date

: November 8, 2007 FCC ID : OZGV680-CHXD

#### 4.2.3 V680-CH1D-PSI



<sup>\*</sup> Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

Desci	scription of EO1 and Support equipment						
No.	Item	Model number	Serial number	Manufacturer	Remarks		
A	RFID READER /	V680-CH1D	RF-DS-07011	OMRON	EUT		
11	WRITER						
В	RFID READER / WRITER	V680-CHUD	RF-DS-07014	OMRON	EUT		
C	RFID READER / WRITER	V680-CH1D-PSI	RF-DS-07012	OMRON	EUT		
D	RFID Tag	V680-D2KF67	7	OMRON	EUT		
Е	AC Adapter	V600-A22	06GT35	OMRON	-		
F	Personal Computer	TYPE 2652-93J	99-PWTVD	IBM	*1)		
G	AC Adapter	02K6746	11S02K6746Z1Z2UF2C41MV	IBM	*1)		
Н	Personal Computer	nx-9040	CNF5201PRQ	HP	-		
I	AC Adapter	PA-1650-02C	5425934606	HP	-		
J	DC power supply	S82K-00705	0767YK		-		
K	RS-232C Converter	-	-	OMRON	-		
L	Mouse	M-UB48	830318-0000	Logitech	*2)		

<sup>\*1)</sup> Used for Conducted emission test

### List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	RS232C cable	2.4	Shielded	Shielded	-
2	DC cable	2.0	Unshielded	Unshielded	-
3	DC cable	1.8	Unshielded	Unshielded	-
4	AC cable	1.8	Unshielded	Unshielded	-
5	RS232C cable	0.7	Shielded	Shielded	-
6	DC cable	0.4	Unshielded	Unshielded	-
7	AC cable	2.0	Unshielded	Unshielded	-
8	RS232C cable	0.1	Unshielded	Unshielded	-
9	USB cable	1.9	Shielded	Shielded	-
10	Mouse cable	0.8	Shielded	Shielded	*2)

<sup>\*2)</sup> Used for Radiated emission test

# UL Japan, Inc.

### **Head Office EMC Lab.**

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8116 : +81 596 24 8124 Facsimile

<sup>\*2)</sup> Used for Radiated emission test

Test report No. : 28AE0160-HO-A-R1
Page : 9 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### **SECTION 5: Conducted emission**

#### 5.1 Operating environment

Test place : No.2 semi anechoic chamber.

Temperature : See data Humidity : See data

### 5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 80cm above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/ an AMN to the input power source. All unused 50ohm connectors of the LISN/ AMN were resistively terminated in 50ohm when not connected to the measuring equipment. The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT on a horizontal conducting plane 4.0 x 4.0m and a vertical conducting plane 2.0 x 2.0m in a semi Anechoic Chamber. A drawing of the set up is shown in the photos of APPENDIX 1.

#### 5.3 Test conditions

Frequency range : 0.15MHz - 30MHz

EUT position : Table top EUT operation mode : See Clause 4.1

### 5.4 Test procedure

The AC Mains Terminal Continuous disturbance Voltage had been measured with the EUT in the semi Anechoic Chamber.

The carrier frequency was measured with an antenna terminal terminated.

The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains Network (AMN). An overview sweep with peak detection has been performed.

The measurements had been performed with a quasi-peak detector and if required, with an average detector. The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : QP and AV IF Bandwidth : 9kHz

#### 5.5 Test result

Summary of the test results: Pass

### UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 28AE0160-HO-A-R1
Page : 10 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

### SECTION 6: Radiated emission (Fundamental, Spurious Emission and Spectrum Mask)

#### 6.1 Operating environment

The test was carried out in a No.1 semi Anechoic Chamber

Temperature : See data Humidity : See data

#### **6.2** Test Procedure

The Radiated Electric Field Strength intensity has been measured in a semi anechoic chamber with a ground plane and at a distance of 3m.

Frequency: From 9kHz to 30MHz at distance 3m, by Loop antenna

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for each antenna angle 0deg., 45deg. and 90deg.

Frequency: From 30MHz to 1GHz at distance 3m, by Biconical antenna and Logperiodic antenna

The measuring antenna height was varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with a QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver.

	From 9kHz to 90kHz	From	From	From	From
	and	90kHz to	150kHz	490kHz to	30MHz to
	From 110kHz to	110kHz	to 490kHz	30MHz	1GHz
	150kHz				
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz

<sup>-</sup> The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

#### 6.3 Test result

Summary of the test results: Pass

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

<sup>\*</sup> FCC Part 15 Section 15.31 (f)(2) / IC RSS-Gen 4.11 (9kHz-30MHz) 9kHz – 490kHz [Limit at 3m]=[Limit at 300m]-40log (3[m]/300[m]) 490kHz – 30MHz[Limit at 3m]=[Limit at 30m]-40log (3[m]/30[m])

Test report No. : 28AE0160-HO-A-R1
Page : 11 of 49
Issued date : October 1, 2007
Revised date : November 8, 2007
FCC ID : OZGV680-CHXD

# **SECTION 7: 20dB Bandwidth**

#### **Test Procedure**

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test data : APPENDIX 2

Test result : Pass

# **SECTION 8: Frequency Tolerance**

#### **Test Procedure**

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test data : APPENDIX 2

Test result : Pass

### **SECTION 9: 99% Occupied Bandwidth**

#### **Test Procedure**

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test data : APPENDIX 2

Test result : Pass

### UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN